

Supplementary Information for

Split-cube-resonator-based metamaterials for polarization-selective asymmetric perfect absorption

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S1. Simulation results for backward illumination of free-standing structure

S2. Field plots of perfect absorption (y linear polarization) vs perfect reflection (x linear polarization) at 27 THz

S3. Oblique incidence results for TE polarization in xz plane

S1. Simulation results for backward illumination of free-standing structure

In the free-standing four-layer SCR structure, forward and backward illumination directions exhibit “reversed” responses for the two polarizations, i.e., the response for the y linear polarization for forward illumination is identical with the response for x linear polarization under backward illumination and vice versa. This is shown in Fig. S1 compiling amplitude reflection and transmission coefficients, as well as the absorption, for all cases.

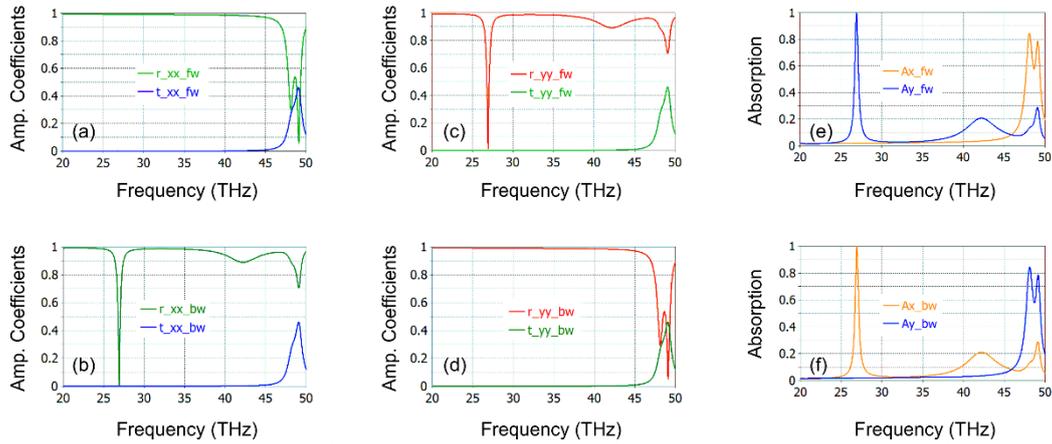


Fig. S1: Simulation results for a free-standing (no substrate) four-layer SCR structure. (a,b) Amplitude reflection and transmission coefficients for the x linear polarization, considering both (a) forward (fw) and (b) backward (bw) illumination. (c,d) Amplitude reflection and transmission coefficients for the y linear polarization, considering both (c) forward (fw) and (d) backward (bw) illumination. (e,f) Absorption for (e) forward (fw) and (f) backward (bw) illumination. The situation is exactly reversed between the two illumination directions.

S2. Field plots of perfect absorption (y linear polarization) vs perfect reflection (x linear polarization) at 27 THz

Fig. S2 depicts the distribution of the surface current density for both polarizations. For E_y excitation [Fig. S2(a)], the field penetrates and interacts with the structure, since the incident H_x field component can couple with the magnetic dipole resonance of the SCR resonators in the first/front layer. The induced current distribution then conductively couples to the other layers. In contrast, the E_x excitation [Fig. S2(b)] cannot excite the magnetic dipole resonance; the front layer behaves in that case as a grid of uniform conducting wires, impeding the coupling of the incident field with the other (inner) SCR layers and leading to almost total reflection.

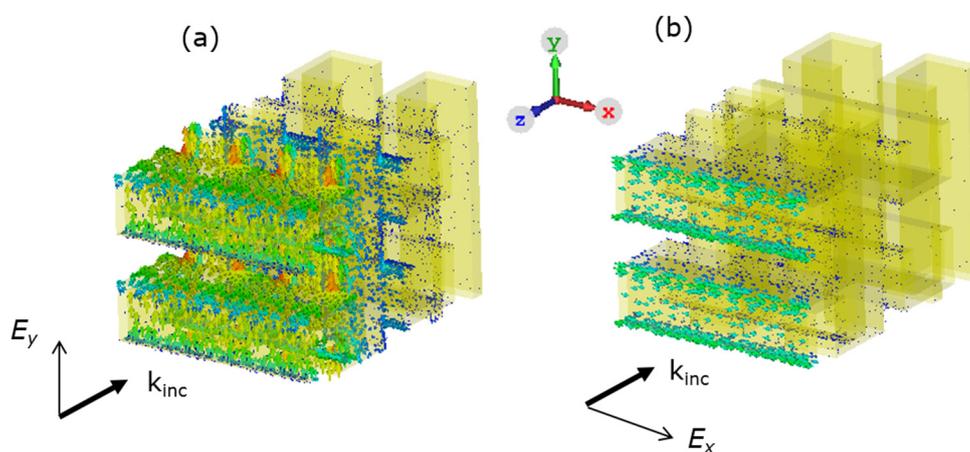


Fig. S2: Distribution of surface current density at 27 THz for (a) y linear polarization incidence and (b) x linear polarization incidence. For E_y excitation, the field penetrates and interacts with the structure, since the incident H_x field component can couple with the magnetic dipole resonance of the SCR resonators in the first/front layer. The induced current distribution then conductively couples to the other layers. In contrast, the E_x excitation cannot excite the magnetic dipole resonance; the front layer behaves in that case as a grid of uniform conducting wires, impeding the coupling of the incident field with the other (inner) SCR layers and leading to almost total reflection.

S3. Oblique incidence results for TE polarization in xz plane

In Fig. S3 it is demonstrated that for TE polarized incidence in the xz incidence plane ($E=E_y\mathbf{y}$), the spectral position of the absorption peak changes with incidence angle. This is because the magnetic field component does not remain parallel to the x axis, in contrast to TM polarization in the yz plane that is discussed in the manuscript (see Fig. 4).

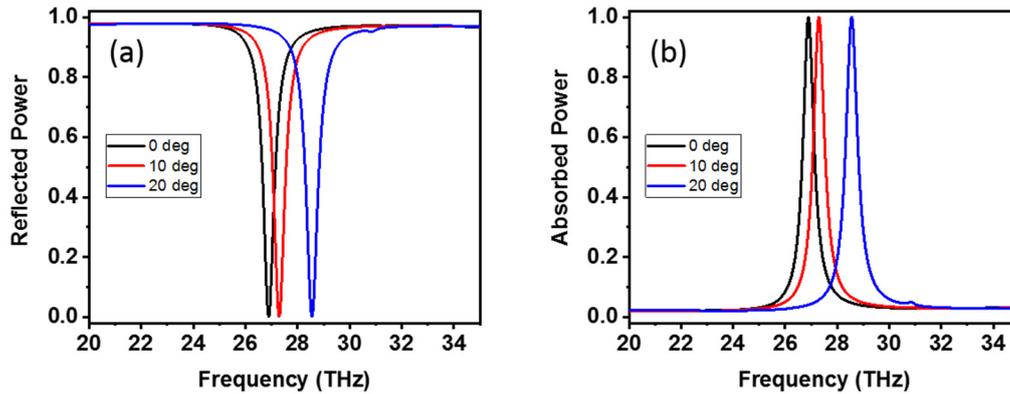


Fig. S3: Oblique incidence performance for TE polarization in the xz incidence plane. Reflection and absorption spectra for different incidence angles: $\theta = \{0, 10, 20\}$ degrees. The performance is independent of the incidence angle. The spectral position of the absorption peak changes with incidence angle, since the magnetic field component does not remain parallel to the x axis.

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